Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	
10/709,370	CHEN ET AL.	
Examiner	Art Unit	

David Nhu

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SEARCHED				
Cla	ass	Subclass	Date	Examiner
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		257, 258		
		197, 259		
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	INTERFERENCE SEARCHED				
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ſ	438	266	4/2/2005	DN	
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